



## Introduction

The SPC564Axx /SPC563Mxx devices target a range of powertrain applications:

- Low to mid range engine management
- Automotive transmission control

The devices are based on the e200zx Power Architecture® core and feature the second version of the enhanced Timing Processor Unit (eTPU2) for advanced, independent timing control operations.

This document aims to provide guidelines to design the ECU hardware in the most efficient way. It is focused on:

- Power Management Controller (PMC)
- FMPLL and oscillator
- Configuration pins and unused IOs
- ADC see [Section 4: ADC](#)
- Reset

# Contents

<b>1</b>	<b>Power Management Controller (PMC)</b> .....	<b>6</b>
1.1	Single 5 V system power supply .....	6
1.1.1	External power supply slew rate .....	6
1.1.2	3.3 V power supply .....	6
1.1.3	1.2 V power supply and regulator controller .....	7
1.1.4	External ballast transistor .....	7
1.1.5	1.2V core regulator external circuitry .....	8
1.1.6	Inrush current .....	11
1.1.7	Layout recommendations .....	12
1.2	External power supply configuration .....	14
1.2.1	Decoupling .....	15
1.2.2	External power supply slew rate .....	15
1.2.3	Power up/down sequencing .....	15
1.3	Mixed configurations .....	15
1.4	Low-Voltage-Inhibit (LVI) .....	15
1.5	Voltage fine tuning .....	16
1.6	Stand-by RAM functionality .....	16
1.6.1	SRAM Standby switch .....	16
1.6.2	Standby Regulator .....	17
1.6.3	Brown-out Detector .....	17
1.7	Power dissipation .....	17
1.7.1	Internal logic power consumption .....	18
1.7.2	Analog power consumption .....	18
1.7.3	Voltage regulator power consumption .....	18
1.7.4	3.3V power consumption .....	18
1.7.5	IOs power consumption .....	18
1.7.6	Package power dissipation .....	18
<b>2</b>	<b>FMPLL and crystal oscillator</b> .....	<b>19</b>
2.1	Crystal oscillator and external circuitry .....	19
2.1.1	External circuitry .....	20
2.1.2	Recommended crystals .....	21
2.2	Crystal or external reference .....	21

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2.3	Bypass mode or normal mode .....	21
2.4	Ramp up .....	21
2.5	Layout recommendations .....	22
<b>3</b>	<b>Configuration pins and unused I/Os .....</b>	<b>23</b>
3.1	Boot modes (SPC564Axx) .....	23
3.2	Boot modes (SPC563Mxx) .....	23
3.3	Clock reference .....	23
3.4	Weak pull configuration .....	24
3.5	RSTCFG (SPC564Axx only) .....	24
3.6	Unused I/Os .....	24
<b>4</b>	<b>ADC .....</b>	<b>25</b>
4.1	Alternative approach .....	30
<b>5</b>	<b>Reset .....</b>	<b>31</b>
5.1	/RESET .....	31
5.2	/RSTOUT .....	31
5.3	Reset source description .....	31
5.4	Reset circuitry example .....	33
<b>Appendix A</b>	<b>Previous recommended PMC network configurations .....</b>	<b>34</b>
<b>Appendix B</b>	<b>Further information .....</b>	<b>36</b>
B.1	Reference documents .....	36
<b>Revision history</b>	<b>.....</b>	<b>37</b>

## List of tables

Table 1.	External network specification .....	10
Table 2.	Miscellaneous decoupling caps .....	11
Table 3.	Fine tuning parameters .....	16
Table 4.	Crystal total load capacitance .....	20
Table 5.	Boot modes .....	23
Table 6.	SPC564Axx / SPC563Mxx ADC parameters .....	25
Table 7.	Reset source description .....	32
Table 8.	Document revision history .....	37

## List of figures

Figure 1. Voltage regulator external components guaranteed configuration 1 ..... 9

Figure 2. Voltage regulator external components guaranteed configuration 2 ..... 10

Figure 3. Inrush current example - without collector resistor ..... 12

Figure 4. Inrush current example - with collector resistor ..... 12

Figure 5. VDD distribution using a small plane example ..... 13

Figure 6. Implementation of decoupling Capacitors. .... 14

Figure 7. System clock diagram. .... 19

Figure 8. Oscillator. .... 20

Figure 9. PCB layout example for SPC563Mxx / SPC564Axx. .... 22

Figure 10. Simplified ADC circuitry ..... 25

Figure 11. Reset circuitry example ..... 33

Figure 12. SPC563Mxx configuration/SPC564Axx configuration ..... 34

Figure 13. Alternate SPC563Mxx configuration. .... 35

# 1 Power Management Controller (PMC)

The SPC564Axx / SPC563Mxx devices require three separate power supplies, nominally:

- 5V (VDDREG, VDDEHx, VDDA);
- 3.3V (VRC33, VDDEHx, VDDEx);
- 1.2V (VDD, VDDPLL);

In addition, an optional 0.95 - 1.2 / 2 - 5.5 V  $V_{stby}$  for the SRAM stand-by functionality may be required<sup>(a)</sup>.

Different modes of operations are possible:

- Single 5V system power supply (SPC564Axx: QFP176 only, SPC563Mxx: QFP144 only)
- Three external power supplies
- 5V and 3.3V provided externally (1.2 V internally controlled)
- 5V and 1.2V provided externally (3.3 V internally generated)

## 1.1 Single 5 V system power supply

The SPC564Axx in QFP176 and the SPC563Mxx in QFP144 devices can operate from a single 5 volt system power supply. An on-chip regulator is provided for 3.3 volts, and an on-chip regulator controller is provided for the 1.2 volt supply. The 1.2 volt controller requires an external NPN ballast transistor and external bypassing for proper operation. This section covers the requirements for the regulator controller and the bypass capacitors for the device.

The Voltage Regulator Supply (VDDREG) is the 5V input to the internal 3.3V regulator and the 1.2 regulator controller. This input can be tied to VSS to disable these feature. However grounding VDDREG disables also the low voltage inhibit (LVI) circuit. Refer to [Section 1.2: External power supply configuration](#) for more details.

The SPC564Axx in BGA324 and the SPC563Mxx in QFP176 devices instead cannot operate from a single 5 volt system power supply. Most of the SPC564Axx EBI interface pins (main difference between BGA324 and QFP176) can't be powered with 5V, therefore an additional external voltage supply (3.3 V) is needed. Similarly, SPC563Mxx QFP176 Nexus pins (ALT\_MDOx, ALT\_MSE0x, ALT\_EVTI, ALT\_EVTO and ALT\_MCKO) must be supplied with 3.3 V.

### 1.1.1 External power supply slew rate

Make sure that all power supply ramps are not too fast and in line to what is specified in the device datasheet. Higher slew rates might cause false ESD trigger.

### 1.1.2 3.3 V power supply

The 3.3V regulator circuitry is completely contained within the device and it requires only the 5V input supply (VDDREG) and a bypass capacitor on the regulator output(s), VRC33. This

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a. Refer to [Section 1.6: Stand-by RAM functionality](#)

3.3V regulator is intended for internally operation only (oscillator, part of FLASH, some Nexus pins) and it must not be used to supply external circuitry or other IOs. Nevertheless, VRC33 can be used as the reference on the debug connector of the JTAG/Nexus interface<sup>(b)</sup>.

Please notice that the JTAG and some Nexus signals (TCK, TDI, TDO, TMS, JCOMP, MSEO[0:1], RDY, MDO[4..11], EVTO, EVTI) even if powered by a nominal 5V supply, VDDEH7, are always operating on 3.3 voltage levels, being MultiV pads configured by default (this setting cannot be changed) in low swing mode. On the other hand, when the same MultiV pads are configured as GPIO (or eTPU), they work on 5V levels (this setting cannot be changed either).

### 1.1.3 1.2V power supply and regulator controller

Most of the internal device circuitry is powered by the 1.2 V VDD input. This includes the core and the majority of the device internal logic. An internal regulator controller is implemented to provide a more cost optimized solution. By using an external ballast transistor, the power loss from reducing the 5 V to 1.2 V can be dissipated externally.

This 1.2V voltage regulator controller provides a current signal (VRCCTL) that drives the base of the external transistor. VDD is internally connected to the a sense signal that is compared to an internal bandgap reference that sets the reference voltage. Depending on VDD the current flowing out of the VRCCTL is adjusted to keep the 1.2 voltage level.

### 1.1.4 External ballast transistor

The following NPN transistors are guaranteed for use with the on-chip voltage regulator controller: ON Semiconductor BCP68T1 or NJD2873 as well as NXP BCP68. The collector of the external transistor is preferably connected to the same voltage supply source as the output stage of the regulator, however it can also be connected to another voltage supply (for example 3.3 V).

Any other transistor type / vendor may not work with the circuitry proposed in the [Section 1.1.5: 1.2V core regulator external circuitry](#) in all the conditions, considering the PVT (Process, Voltage, Temperature) worst cases.

#### Gain

The maximum current available or the VDD supply depends on the gain of the NPN transistor used, it should be high enough to allow the operation in the worst case scenario in terms of current consumption, given the minimum current that can be sourced by VRCCTL<sup>(c)</sup>.

From the SPC564Axx point of view, the worst case is at hot, the device may require up to 450mA<sup>(d)</sup> on the VDD. On the other hand, usually the worst case gain is obtained at cold.

b. IEEE-ISTO 5001™ - 2003 extract: "The VREF signal is used to establish the signaling levels of the debug interface of the target system. Any current drawn from this pin should be limited to that needed for voltage translation and/or signal interpolation and is not intended to supply logic functions or power. VREF is not necessarily at the target processor VDD level."

c. Please refer to device DS.

d. Preliminary data. Check the latest DS for updated figures.

In addition the transistor gain should not be too high otherwise the regulator may become unstable.

### Power dissipation

Another important point is that the external transistor must be able to dissipate the power due to the voltage drop. The worst case is calculated as follow:  $(VDDREG_{max} - VDD_{max}^{(e)}) * IDD_{max} = (5.25 - 1.32) * 0.450 = 1.768W$ . Depending on the package, this power might not be dissipated. For example, if the total thermal resistance is 25C/Watt,  $T_j = 150C$  e  $T_{amb} = 125C$ , 1W is the maximum allowed. Sometimes a heatsink is required to reduce the overall thermal resistance and thus increase the power dissipation.

An optional collector resistor can help in sharing the power dissipation. For example a 2 Ohm resistor on the collector reduce the voltage drop between collector and emitter by 0.9 V. In this case the transistor has to dissipate only  $(5.25 - 1.32 - 0.9) * 0.450 = 1.3635W$ .

### Ballast transistor saturation voltage

On the other hand, the value of the collector resistor cannot be too high because the transistor must always be operating out of the saturation region:  $VCE > VCE_{sat}$ . For example, if the  $VCE_{sat} = 0.3V$ ,  $R_{max} = (VDDREG_{min} - VDD_{max} - VCE_{sat}) / IDD_{max} = (4.75 - 1.32 - 0.3) / 0.45 = 7.6$  Ohm.

## 1.1.5 1.2V core regulator external circuitry

In the [Figure 1](#) and [Figure 2](#) are shown the guaranteed configuration of the external components<sup>(f)</sup>. Collector and emitter caps should be the same type capacitors; otherwise series impedance mismatch require bigger bypass capacitor on the 5V supply. The value of the collector cap can be reduced to the ones of the emitter to allow the matching.

The ground connection is also critical and must be as close as possible to the mandatory  $V_{DD}$  capacitor bank to be effective.

The snubber circuit on the base is required for stability reasons.

e. The worst case is normally with  $VDD = 1.12V$ , however the max current is specified when  $VDD = 1.32V$ .

f. Refer also to [Appendix A: Previous recommended PMC network configurations](#)



Figure 1. Voltage regulator external components guaranteed configuration 1

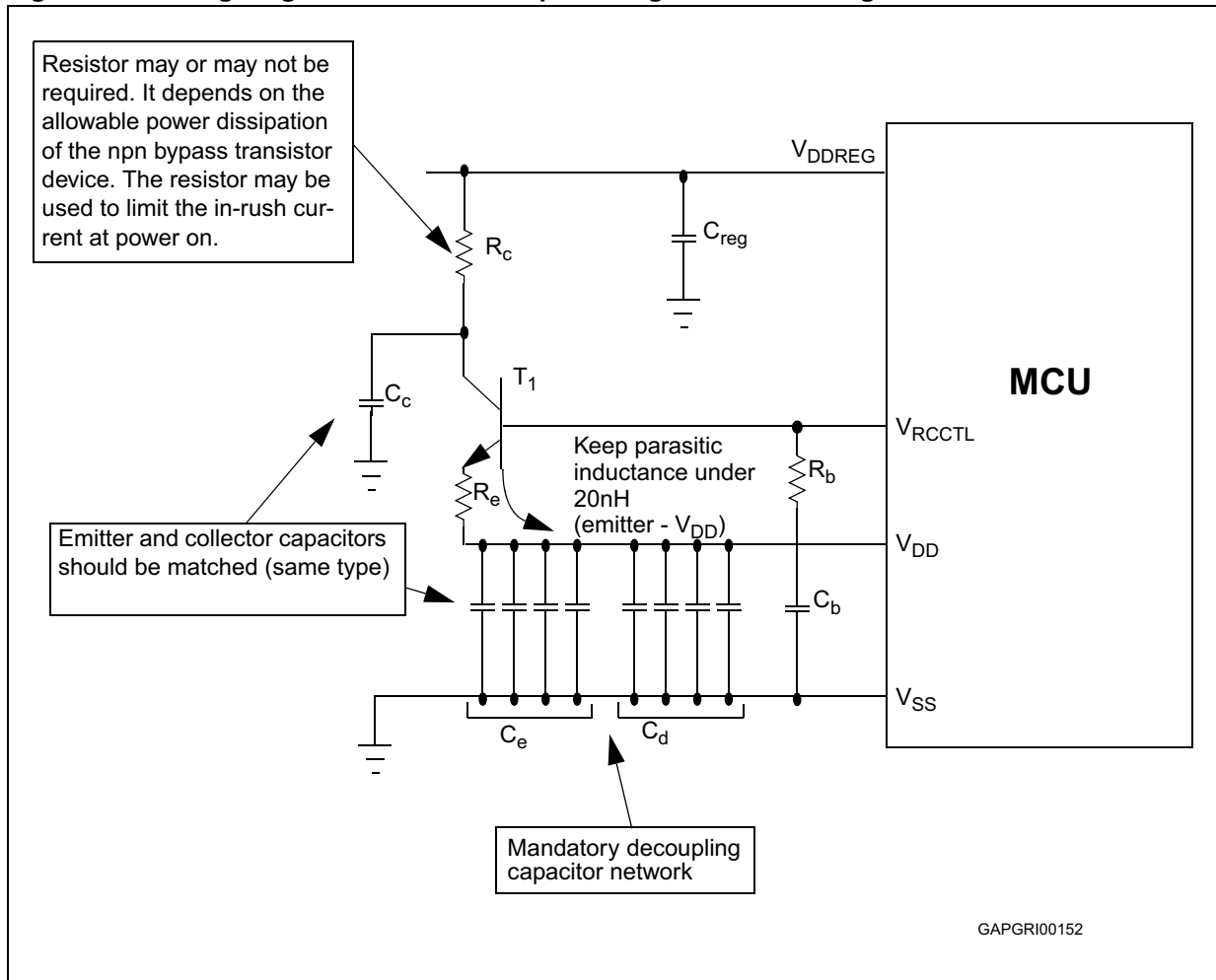


Figure 2. Voltage regulator external components guaranteed configuration 2

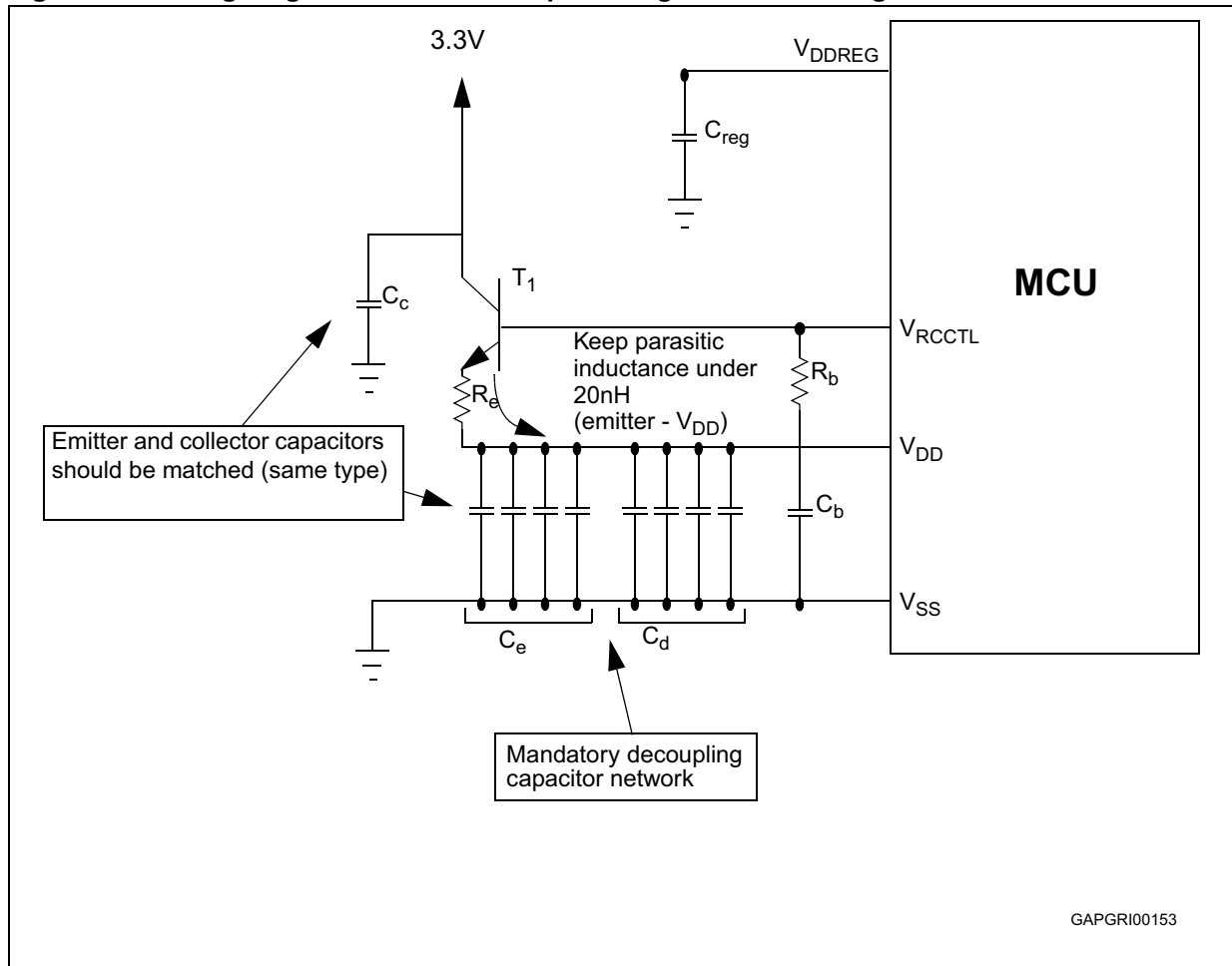


Table 1. External network specification

External component	Min.	Typ.	Max.	Notes
T1				NJD2873 or BCP68 only
C <sub>b</sub>	1.1uF	2.2uF	2.97uF	X7R, -50% / +35%
C <sub>e</sub>	3 x 2.35uF + 5uF	3 x 4.7uF + 10uF	3 x 6.35uF + 13.5uF	X7R, -50% / +35%
Equivalent ESR of C <sub>e</sub> capacitors	5mOhm		50mOhm	
C <sub>d</sub>	4 x 50nF	4 x 100nF	7 x 135nF	X7R, -50% / +35% In order to have one cap on each VDD (EMC rules), depending on the package the number of these capacitors may be increased up to 7x100nF. 700nF is the absolute max allowed: it can be also split in 12x56nF or 17x47nF.
R <sub>b</sub>	90ohm	100ohm	110ohm	+/-10%

Table 1. External network specification (continued)

External component	Min.	Typ.	Max.	Notes
$C_{reg}$		10uF		Depending on the 5V regulator impedance, the required capacitor can go up to 100uF
$R_c$	1.1Ohm		5.6Ohm	May or may not be required. It depends on the allowable power dissipation of $T_1$
$R_e$	0.18Ohm	0.20Ohm	0.22Ohm	+/-10% The required value can be obtained by using more resistors in parallel

Table 2. Miscellaneous decoupling caps

Supply	Quantity	Value	Notes
VRC33	1	470nF - 2uF	Low ESR (<50mOhm)
VSTBY	1	10nF	To be grounded if the Stand-by feature is not used.
VDDPLL	1	100nF	
	1	10nF	
VDDEHx	4	100nF	Two pairs each side
	4	1nF	
VDDA	1	10uF	To be connected between VDDA and VSSA
VRH	1	10nF	
VRL			
VSSA			
REFBYPC	1	100nF	REFBYPC is not a supply. The external bypass capacitor must be placed between REFBYPC pin and GND.

### 1.1.6 Inrush current

Since big capacitors need to be charged, a large current can be required when the power is turned on, to be more precise when the 1.2V regulator is switched on.

A soft-start circuitry is included in the 1.2V regulator but the ramp is only limited to 60-80us (PVT variation), being ineffective for limiting the inrush current.

As already pointed out in the [Section 1.1.4](#), the resistor on the collector may or may not be required depending on the allowable power dissipation of the ballast transistor. However the resistor on the collector can be also very useful in limiting the current necessary to charge the capacitors during power on.

Figure 3. Inrush current example - without collector resistor

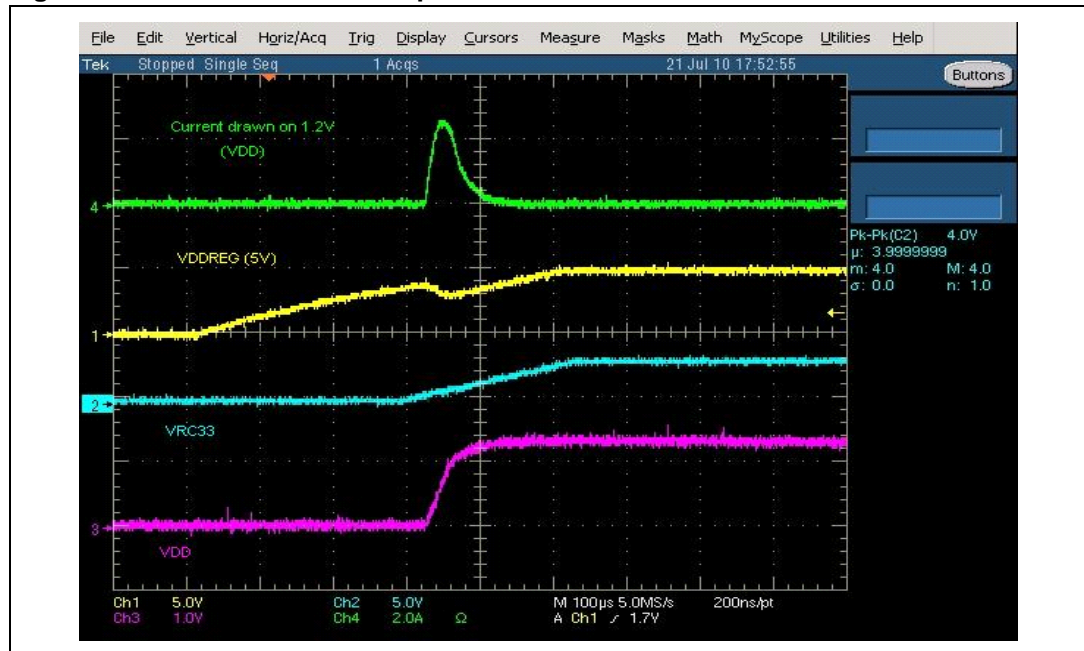
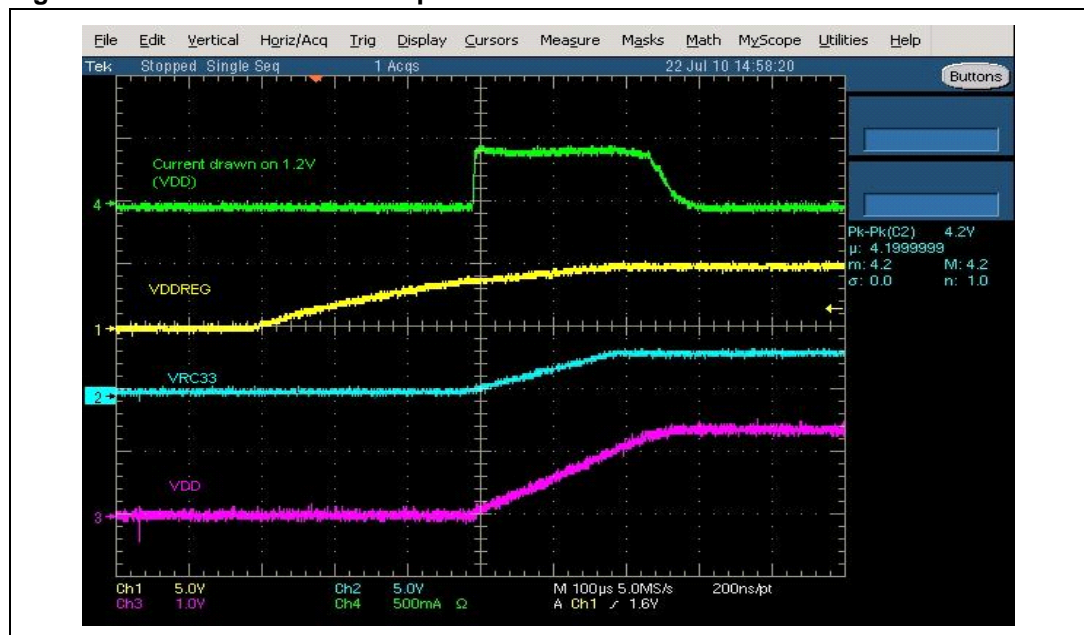


Figure 4. Inrush current example - with collector resistor



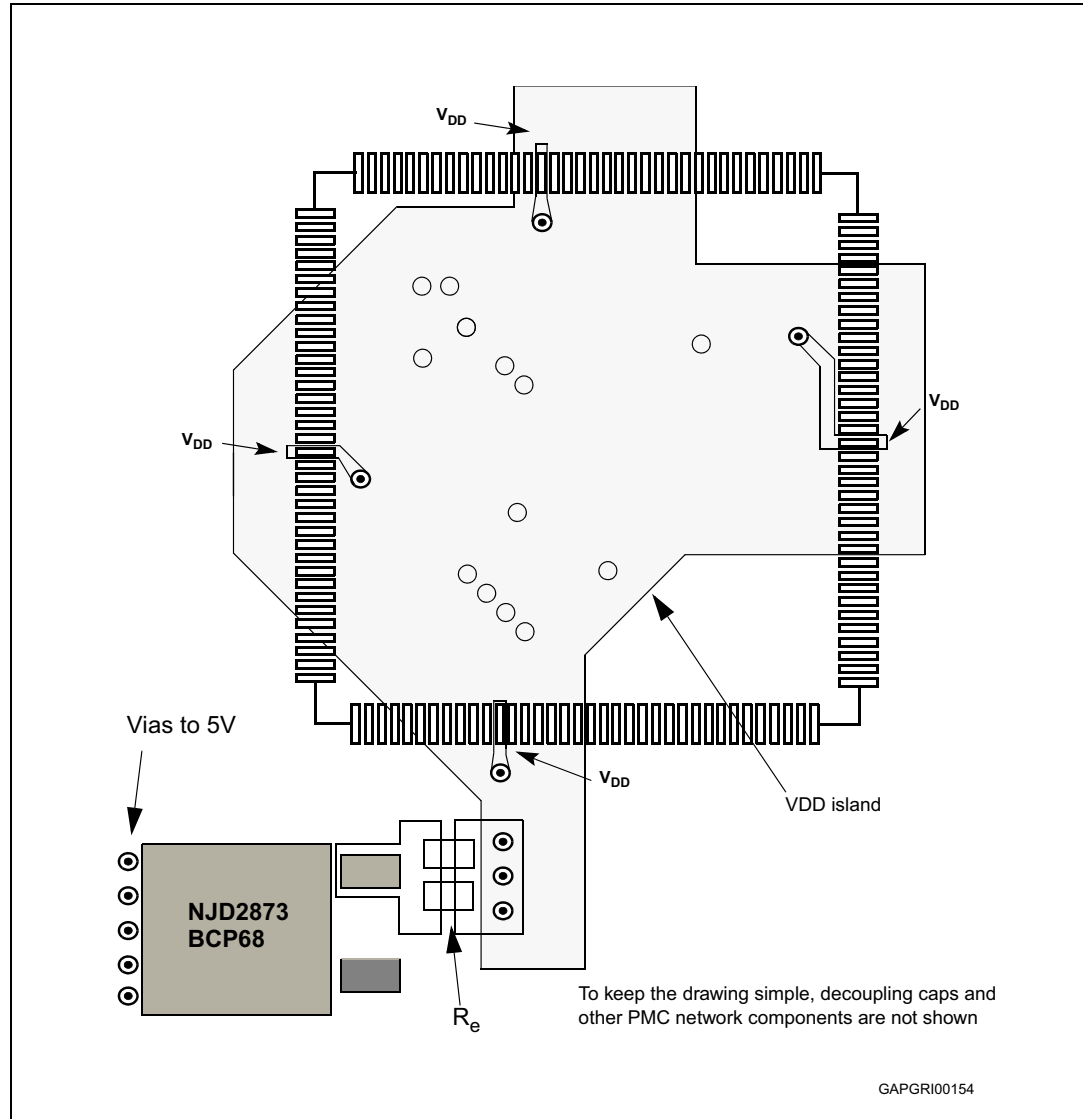
### 1.1.7 Layout recommendations

The inductance of the heatsink rail of the ballast transistor and the MCU lead to inductance in the system. The placement of the transistor also affects the inductance, due to the lengths of the 1.2 V traces (from the emitter to the  $V_{DD}$  pins) and of the VRCCTL signal: those inductances eventually reduce the phase margin jeopardizing the regulator stability.

*It is mandatory to keep the parasitic inductance between the emitter and  $V_{DD}$  pins lower than 20nH.*

Use preferably a small plane to distribute  $V_{DD}$  with a low parasitic inductance to each pin. Using of multi-layer printed circuit board (PCB) with a separate layer dedicated to the ground and another one to the voltages supply is also advised. If the small plane approach is not possible, try to keep short and wide the traces between the ballast transistor and the micro and the layout compact to reduce the parasitic.

**Figure 5.  $V_{DD}$  distribution using a small plane example**



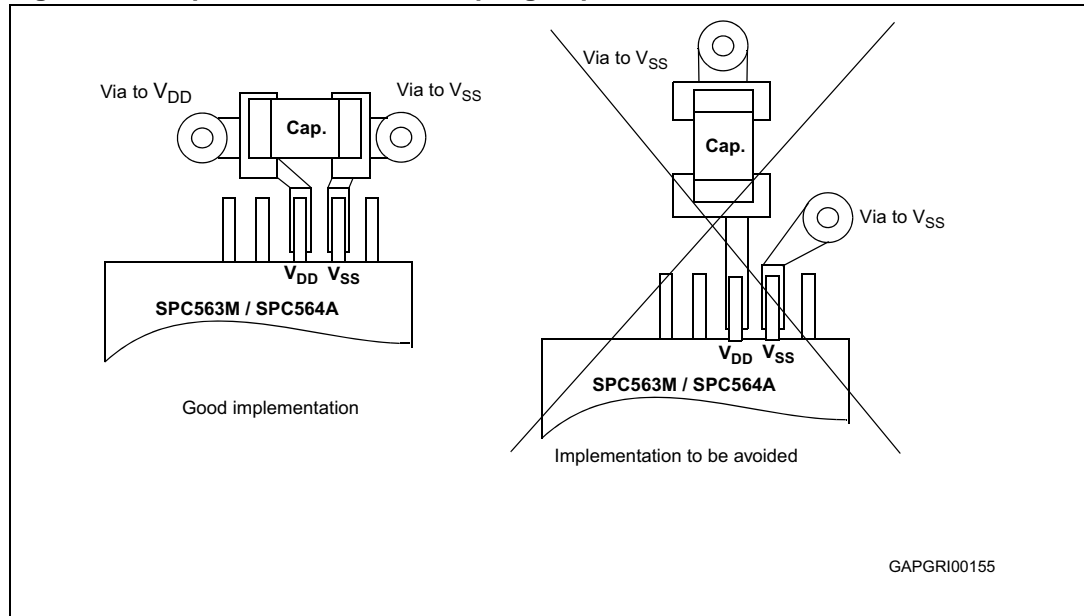
Possibly, the ground plane should be adjacent to the VDD island, with a thin dielectric. This build a good quality HF capacitor. Moat at least 1 to 3 mm between the different power planes, never overlap them. Use multiple vias to connect to inner layers. This reduce the inductance, being the vias parasitic inductance in parallel.

Decoupling capacitors are placed as close as possible to the VDD/VSS pair:

- connected to both VDD and VSS pins (closest pins);
- connected to each VDD/VSS pair.

For EMC reasons, decoupling capacitors are connected to the VDD and VSS of adjacent pins. This is illustrated by [Figure 6](#).

**Figure 6. Implementation of decoupling Capacitors**



Do not place one or more caps close to the transistor emitter in order to avoid potential resonant CLC network (emitter cap(s) -> parasitic inductance -> VDD caps).

## 1.2 External power supply configuration

In this configuration the three voltage levels required are provided externally: VRCCTL can be left floating, VRC33 becomes the input of the 3.3 voltage and VDD pins/balls must be connected to the 1.2 V source.

In order to switch off the internal 3.3 voltage regulator, two solutions are possible:

1. VDDREG = GND

Disabling the regulator using this option implies disabling also the Low Voltage Inhibit circuit.

### SPC564Axx

2. vrc3p3\_shutdown\_shadow\_bit = 0 (bit 31, least significant bit) in the FLASH\_BIU4 register (0xC3F8\_802C)<sup>(g)</sup>

The default value after reset of the volatile register FLASH\_BIU4 can be modified by programming the shadow FLASH location 0x00FF\_FE10.

### SPC563Mxx

3. V33EN = 0

<sup>g</sup> The internal 3.3 V regulator is always switched on during reset.

V33EN is the least significant bit of the NVUSRO (Non-Volatile User Options Register - Array 0). This location is inside the shadow block (0x00FF\_FE18).

Please refer to the device RM to get more details on how to program the shadow block.

**Caution:** Note that a wrong erase/programming of the shadow block may get the device definitively censored and therefore unusable.

### 1.2.1 Decoupling

Decoupling network(s) are designed taking in account the external voltage supply requirements.

### 1.2.2 External power supply slew rate

Make sure that all power supply ramps are not too fast and in line to what is specified in the device datasheet. Higher slew rates might cause false ESD trigger.

### 1.2.3 Power up/down sequencing

There is no power sequencing required among power sources during power up and power down, in order to operate within specification but use of the following sequence is strongly recommended when the internal regulator is bypassed:

5 V -> 3.3 V and 1.2 V

This is also the normal sequence when the internal regulator is enabled.

## 1.3 Mixed configurations

According to the main voltage regulator type, the user can decide to choose mixed configurations:

- 1.2V internally regulated with NPN ballast and 3.3 V regulator disabled;
- 3.3V internally generated and 1.2 V provided externally.

For these cases the same recommendations described in the previous paragraphs are still valid.

## 1.4 Low-Voltage-Inhibit (LVI)

The SPC564Axx PMC also implements a low voltage detection circuit that is able to issue either a reset or an interrupt request to the core. LVI resets and interrupts are only enabled when the voltage regulator is enabled (VDDREG=5 V). If the user grounds VDDREG (VDDREG = 0 V) and supplies the voltages externally (1.2 V and 3.3 V), it is also necessary to provide the LVI monitoring externally.

The PMC\_MCR (Module Configuration Register) allows the user to configure which action an LVI event triggers. By default the PMC is configured to issue a reset. To enable application to report an LVI event, the reset has to be disabled and the interrupt enabled by acting on the right bits inside the MCR. Please refer to the product RM to get more details.

*Note:* The user must make sure that the ISR has finished before the voltage sinks below its functional specification and this may require an increase in the LVI level<sup>(h)</sup>.

## 1.5 Voltage fine tuning

The PMC\_TRIMR (Trimming Register) enables the user to fine tune the voltage of the regulators and the LVI thresholds. This register can be write protected by setting the trimming lock bit in the PMC\_MCR.

**Table 3. Fine tuning parameters**

Parameter	Min. (V)	Default (V)	Max (V)
LVI 5V trimming	4.13	4.29	4.43
VREG 3.3V trimming	3.15	3.39	3.60
LVI 3.3V trimming	2.93	3.09	3.23
VREG1.2V trimming	1.12	1.28	1.42
LVI 1.2V trimming	1.0	1.16	1.30

**Caution:** Fine tuning may end-up in non-guaranteed operating conditions, please refer to the product datasheet for the maximum operating conditions.

## 1.6 Stand-by RAM functionality

The SPC564Axx / SPC563Mxx include up to 192 KB of general-purpose SRAM. The first 32 KB of SRAM is powered by its own power supply pin during standby operation.

The Standby mode preserves contents of the standby portion of the memory when the 1.2 V (VDD) power drops below the level of the standby power supply voltage. There are two possible supplies for standby: 0.95-1.2 V directly from the VSTBY pin and 2 – 5.5 volts (also on the VSTBY pin), which enables a standby regulator.

Updates to the standby portion of the SRAM are inhibited during system reset or during Standby Mode.

### 1.6.1 SRAM Standby switch

The SRAM Standby Switch provides selection of standby power to the standby SRAM. The switch selects between the core power supply VDD and an internal regulated voltage generated from the VSTBY supply.

When VDD falls below 0.95V, the switching occurs and the RAM is on the standby supply. At the same time, a power down signal is sent to the RAM to power it down to a safe mode state.

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h. Refer to section [1.5: Voltage fine tuning](#)



The standby switch breaks before make, and hence is not shorted Vdd to Vstby during the transition.

- When the switch sources Vdd\_array from Vstby, and Vdd ramps high, the switch transitions to sourcing Vdd anywhere while  $0 < Vdd - Vstby < 0.050V$  is valid
- When the switch sources Vdd\_array from Vdd, the switch is designed to transition to Vstby when  $Vstby > Vdd$
- The switch works with all ramp rates of Vdd
- The circuit is not draw excessive leakage current if Vdd remains at a mid-level

If VSTBY is not used, it must be connected to ground. When VSTBY is grounded, the switch is always connected to VDD.

### 1.6.2 Standby Regulator

The purpose of the regulator is for when VSTBY is in the range of 2V-5.5V. The regulated output is 1V. When the standby voltage is in the range of 0.95V-1.2V, the regulator is bypassed and the RAM sees the raw, unregulated standby voltage.

### 1.6.3 Brown-out Detector<sup>(i)</sup>

The brown-out detector monitors the standby voltage and sets the BRW flag on the PMC Configuration and Status Register when the voltage on the VSTBY pin falls to 600 mV. After reset, this flag comes up asserted and then it can be cleared by software by writing 1 to it. When the voltage on the VSTBY pin is 0, the brownout detector flag is also 0, regardless of the voltage on VDD.

## 1.7 Power dissipation

The total power dissipation depends on the current required on the different supplies. It also depends on the power configuration. In the single 5V supply configuration, the contributors are:

1.  $VDD * IDD$
2.  $VDDA * IDDA$
3.  $VDDREG * IDDREG$
4.  $VDDEHx * IDDEHx$

If the internal 3.3V voltage regulator is switched off the contributors are:

1.  $VDD * IDD$
2.  $VDDA * IDDA$
3.  $VDDREG * IDDREG^{(j)}$
4.  $VRC33 * IDD33$
5.  $VDDEHx * IDDEHx$

i. Please refer to device errata sheet to check whether or not this feature is available.

j. If the internal 3.3V is switched off but VDDREG is not grounded, there is still a small current consumption due to the LVI circuitry and the 1.2V regulator.

### 1.7.1 Internal logic power consumption

Most of the logic is powered by the 1.2V. In the worst case, the power that must be dissipated internally is given by the maximum VDD voltage multiplied by the maximum current required:  $VDD_{max} * IDD_{max}$ .  $IDD_{max}$  normally depends on the operating frequency.

### 1.7.2 Analog power consumption

In the worst case the power required by the ADC that must be dissipated internally is given by the maximum VDDA voltage multiplied by the maximum current required:  $VDDA_{max} * IDDA_{max}$ . The analog current consumption does not depend on the system operating frequency.

### 1.7.3 Voltage regulator power consumption

The internal 3.3V regulator uses the 5V provided on the VDDREG to generate the 3.3V. The same voltage is used to supply the 1.2V regulator. The worst case scenario is:  $VDDREG_{max} * IDDREG_{max}$ . When disabled but VDDREG is still powered, there is still a small current consumption due to the LVI circuitry and the 1.2V regulator.  $IDDREG$  does not depend on the operating frequency.

### 1.7.4 3.3V power consumption

When in single supply configuration, the 3.3V is generated internally, therefore the current consumption is already taken in account in the maximum  $IDDREG$ .

When the 3.3V is provided externally, the  $IDD33$  current must be taken in account:  $VRC33_{max} * IDD33_{max}$ .  $IDD33$  does not depend on the operating frequency.

### 1.7.5 IOs power consumption

This power consumption depends on the application: pad type, load, switching frequency, voltage and slew rate. The current consumption of the pads is specified in the device datasheet for a given load and a given frequency. The other cases can be extracted from the given data assuming a linear behavior. For example, in the table is shown that a slow pad with 50pF load switching at 4MHz consumes in average 0.5mA. If in the application the pad is switching only at 20KHz (assuming the same load), the average consumption is  $0.5 * 20000 / 4000000 = 2.5\mu A$ . Assuming  $V_{DDEH} = 3.3V$ , the power is:  $3.3 * 2.5 E-6$ .

### 1.7.6 Package power dissipation

Once computed all the power requirements, given a operating temperature and package (and PCB), it is possible to compute whether or not the power can be dissipated in the package. The limit is the junction temperature; for this family of devices  $T_j = 150C$ .

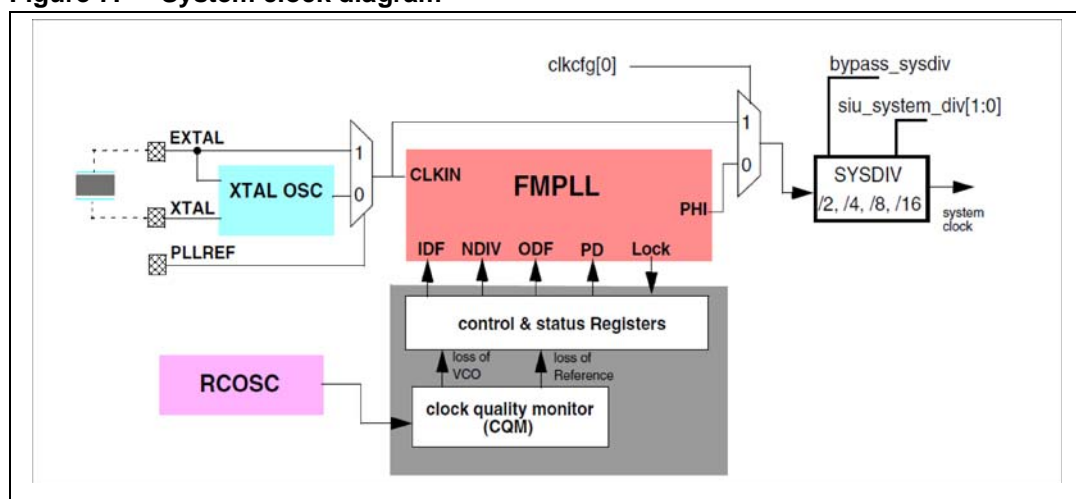
Let's assume that the operating temperature is  $T_{amb} = 100C$  and the total thermal resistance is  $R_{\theta JA} = 19C/W$ , then the maximum power that can be dissipated is  $(T_j - T_{amb}) / R_{\theta JA} = 2.63W$ .

## 2 FMPLL and crystal oscillator

The frequency modulated phase locked loop (FMPLL) allows the user to generate high speed system clocks from a crystal oscillator or from an external clock generator. The onchip oscillator is designed to operate in the range 4-40MHz (SPC563Mxx: 4-20MHz). The frequency modulation is register programmable (frequency and depth). The clock quality module (CQM) provides loss-of-clock detection for the FMPLL reference and output clocks comparing these with the internal RC reference<sup>(k)</sup>. The lock detection circuitry reports when the FMPLL has achieved frequency lock and continuously monitors lock status to report loss-of-lock conditions.

The FMPLL is powered through the VDDPLL/VSSPLL supply couple while the onchip oscillator is powered by the internal 3.3V regulator (or external 3.3V supply).

**Figure 7. System clock diagram**



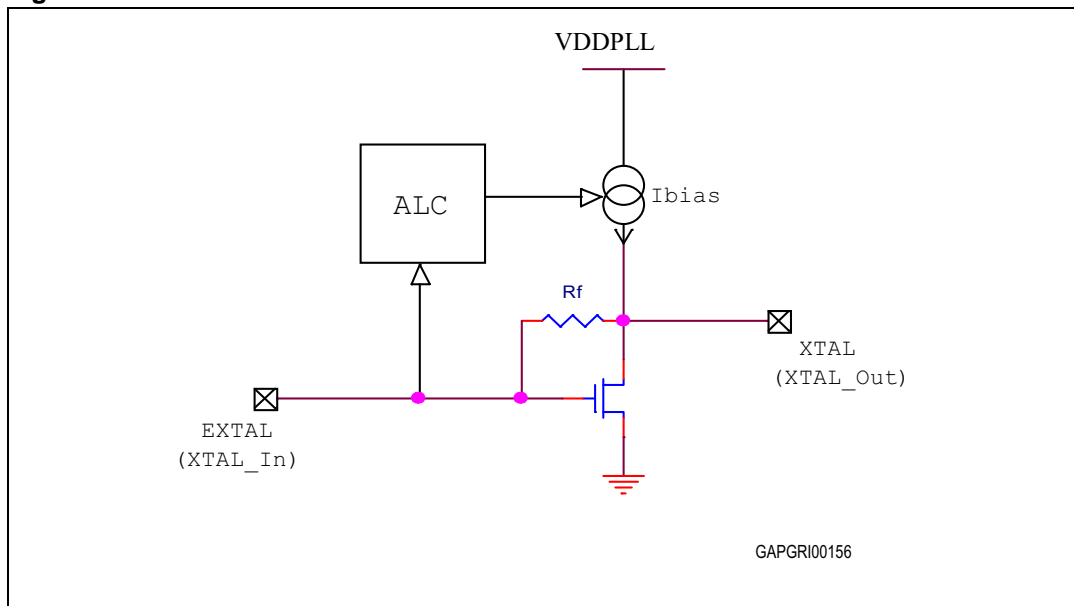
### 2.1 Crystal oscillator and external circuitry

The crystal oscillator circuit is designed and used to provide reference clock to the PLL. Input to the circuit is a sinusoidal input generated by a crystal with an amplifier. Output is a square wave which is used as a reference clock to the PLL.

The type of oscillator is a Pierce CMOS crystal one. This oscillator, however, has an Automatic Level Controller where the amount of current sourced into the amplifier is inversely proportional to the amplitude of the input signal EXTAL. The EXTAL and XTAL signals are then fed to inputs of a comparator to generate a square-wave signal. The crystal oscillator may provide a reference clock to the FMPLL.

k. The internal RC oscillator cannot be used as system clock.

Figure 8. Oscillator



### 2.1.1 External circuitry

The external circuitry normally consists of:

- The crystal
- Two load capacitors
- Serial resistor (optional)

The bias resistor is not needed because it is internally implemented.

The maximum value of the total load capacitance is given by the following table:

Table 4. Crystal total load capacitance<sup>(1)</sup>

XTAL load capacitance	Min. (pF)	Max (pF)
4 MHz	5	30
8 MHz	5	26
12 MHz	5	23
16 MHz	5	19
20 MHz	5	16
40 MHz	5	8

The circuitry design may need also to take in account parasitic capacitance.

1. This value is determined by the crystal manufacturer and board design. For 4 MHz to 40 MHz crystals specified for this PLL, load capacitors should not exceed these limits.

### 2.1.2 Recommended crystals

The following quartzes have been characterized (reports are available on demand):

- NX8045GB 4MHz
- NX5032GA 8MHz
- NX3225GA 16MHz
- NX5032GA 40MHz (SPC564A only)

## 2.2 Crystal or external reference

The configuration pin PLLREF configures the FMPLL clock reference at reset:

- Asserted - Indicates that the reference clock comes from the crystal oscillator
- Negated - Indicates that the reference clock comes from the external clock generator. In this case the external clock source must be connected to the EXTAL pin while XTAL must be grounded.

Assertion or negation of the PLLREF<sup>(m)</sup> must be done at the beginning of the reset cycle and kept stable for the whole reset duration.

*Note:* PLLCFG1 (SPC564Axx BGA324 only) has no PLL configuration functionality anymore. The name has been kept for legacy reasons.

## 2.3 Bypass mode or normal mode

In the bypass mode the FMPLL is completely bypassed and the system clock is driven either from either the crystal oscillator or by an external clock generator connected to the EXTAL pin. Bypass mode is the default mode at reset.

In the normal mode the FMPLL receives an input clock frequency from either the crystal oscillator or by an external clock generator and multiplies the frequency to create the FMPLL output clock.

## 2.4 Ramp up

As already mentioned, the default system clock after reset is derived from the oscillator.

During ramp-up, it is not desirable to set the FMPLL to jump directly to full operating frequency. The frequency can be stepped, with delays to allow the power supply to settle. For example, the target operating frequency of 150MHz (SPC564Axx only) can be reached in three steps: first to 40MHz, then 80MHz and finally 150MHz.

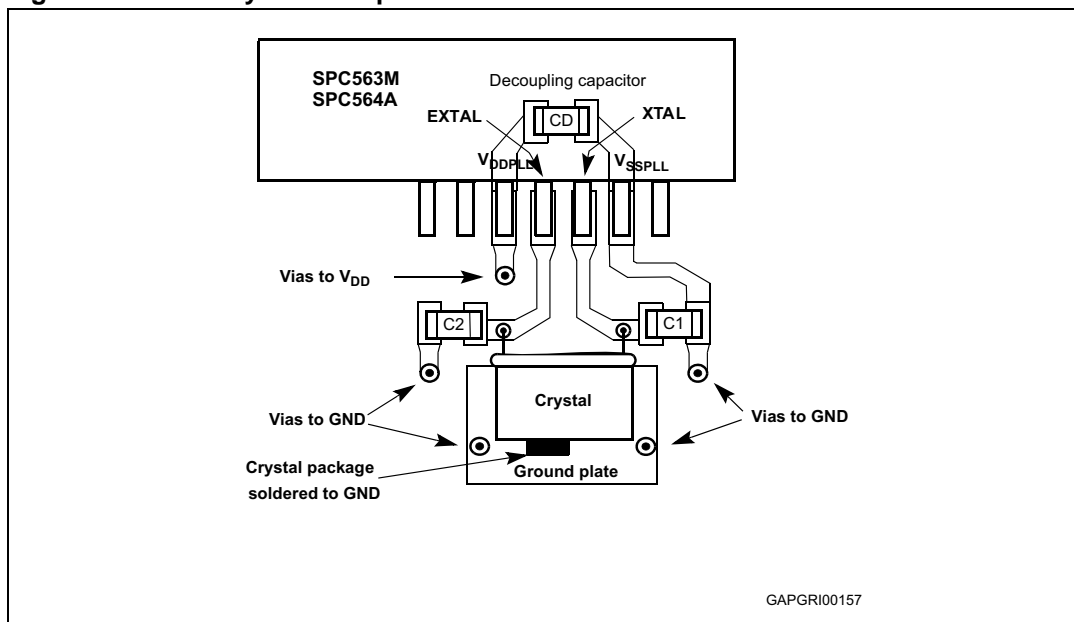
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m. Refer to the Chapter 3: [Configuration pins and unused IOs](#) for more details.

## 2.5 Layout recommendations

- Keep the area of the oscillator circuit as compact as possible, keep tracks very short;
- Avoid any track crossing the oscillator area, also considering inner layers between the components and the ground plane;
- Keep the routing on one layer;
- Create an island for the oscillator ground on the top layer;
- Open all the inner layers in correspondence of the oscillator to reduce capacitance;
- Surround the oscillator area on component side with a GND guard, do not fill the area with ground. To be effective, the guard trace must be grounded by vias every a short length ( $< \text{wavelength} / 20$ , with reference at the higher frequency present);
- Use robust SMT pads for components in crystal oscillator, short track lengths for all signals.

Figure 9. PCB layout example for SPC563Mxx / SPC564Axx



### 3 Configuration pins and unused IOs

In the SPC564Axx / SPC563Mxx there are many configuration pins, they allow to choose the boot mode, the clock reference and the weak pull-up/pull-down configuration:

- BOOTCFG0 (SPC564Axx only), BOOTCFG1
- PLLREF
- WKPCFG
- RSTCFG (SPC564Axx only)

For legacy reasons, PLLCFG1 is still described in the documentation but there is no configuration functionality assigned to this pin any longer.

After the reset those pins can be used as GPIO or any of the other functions available.

#### 3.1 Boot modes (SPC564Axx)

BOOTCFG0 and BOOTCFG1 allow the selection of the boot mode. In the QFP176 package only BOOTCFG1 is available outside while BOOTCFG0 is pulled low internally.

**Table 5. Boot modes**

BOOTCFG[0:1]	Boot Mode Name
00	Internal boot (from FLASH)
01	Serial boot (eSCI / FlexCAN)
10	External boot
11	Reserved

By default both signals are pulled down after reset. If needed, BOOTCFG pins must be pulled high to VDDEH6. The reset controller latches the value on the BOOTCFG[0:1] input to the SIU\_RSR (Reset Status Register) four clock cycles prior to the negation of RSTOUT. The BAM reads the BOOTCFG status from the SIU\_RSR and acts accordingly.

Boot from external bus interface is obviously possible only on the BGA324 package.

#### 3.2 Boot modes (SPC563Mxx)

BOOTCFG1 allows the selection of the boot mode:

- BOOTCFG = 0, internal boot (form FLASH)
- BOOTCFG = 1, serial boot (eSCI / FlexCAN)

BOOTCFG1 is pulled down after reset by default.

#### 3.3 Clock reference

As described in the section [Section 2.2: Crystal or external reference](#), the PLLREF pin determines the source of the reference clock, either crystal or external at the negation of the /RSTOUT. During assertion of the /RSTOUT, the system clock switches to the input

specified by the PLLREF pin. The value on the PLLREF pin must be kept constant during reset to avoid transients in the system clock.

### 3.4 Weak pull configuration

The signal on the WKPCFG pin determines whether specified eTPU and eMIOS pins are connected to weak pull up or weak pull down devices at reset (see the Signal Description chapter in the Reference Manual for the eTPU and eMIOS pins that are affected by WKPCFG). For all reset sources except the Software External Reset, the WKPCFG pin is applied at the assertion of the internal reset signal (assertion of RSTOUT). If the WKPCFG signal is logic high at this time, pull up devices is enabled on the eTPU and eMIOS pins. If the WKPCFG signal is logic low at the assertion of the internal reset signal, pull down devices are enabled on those pins. The value on WKPCFG must be held constant during reset to avoid oscillations on the eTPU and eMIOS pins caused by switching pull up/down states. The final value of WKPCFG is latched four clock cycles before the negation of RSTOUT. After reset, software may modify the weak pull up/down selection for all I/O pins through the PCR registers in the SIU.

### 3.5 RSTCFG (SPC564Axx only)

RSTCFG is used to enable or disable the PLLREF and the BOOTCFG[0:1] configuration signals:

- 0: Get configuration information from BOOTCFG[0:1] and PLLREF
- 1: Use default configuration of booting from internal flash with crystal clock source

*Note:* For the 176-pin QFP package RSTCFG is always 0, so PLLREF and BOOTCFG signals are used.

RSTCFG pin allows, for example, to select the most common configuration without the need of having pulling up/down on several pins.

### 3.6 Unused I/Os

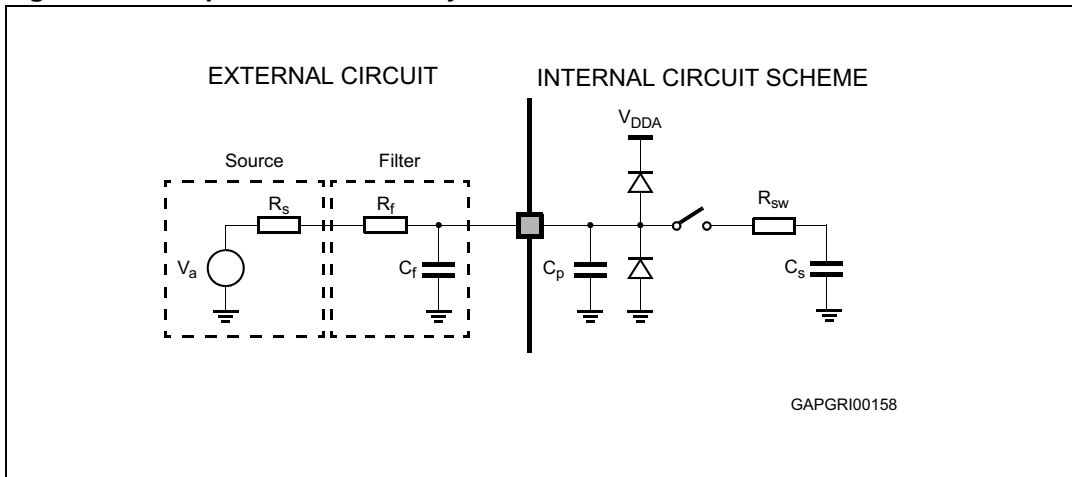
With respect to power consumption, there is no particular recommendation for unused I/Os: both input and output buffers are disabled after reset. However, from the EMC perspective, it is always desirable to tie unused pins to ground or supply voltage, also through internal pull-up/down resistors (enabled by default).



# 4 ADC

The goal of this chapter is to provide hints on how to dimension correctly the external ADC circuitry in order to reduce errors and, at the same time, to protect the ADC inputs.

**Figure 10. Simplified ADC circuitry**



The [Figure 10](#) shows a simplified scheme of the external and internal circuit.

**Table 6. SPC564Axx / SPC563Mxx ADC parameters**

Parameter	Min.	Nominal	Max
$C_p$	-	-	12pF
$R_{sw}$	-	8KOhm	21KOhm (3 sigma, 150C)
$C_s$ (single ended)	-	-	0.8pF
$C_s$ (differential)	-	-	1.3pF
ADC clock frequency	-	-	16MHz
Sampling time (ADC clocks)	2	-	128
12bit single ended conversion time (ADC clocks)	-	14	-
12bit differential conversion time (ADC clocks)	-	13	-
Residual voltage on sample capacitor	1.25V	-	3.75V

The external analogue source can be represented as a voltage source with its impedance ( $R_s$ ). Then it is a common practice to put an RC circuit to filter the analogue source; in addition  $R_f$  can be also useful as current limiter in case of overvoltage.

The internal circuitry can be represented by:

- $C_p$ , pin capacitance, including other parasitic capacitance;
- $R_{sw}$ , switching resistance, including the multiplexer and the sampling switch resistance;
- $C_s$ , the sampling capacitance.

The first constraint comes from the current limitation.  $R_f$  must be chosen to limit the injection current:

#### Equation 1

$$R_s + R_f \geq \frac{V_{amax} - (V_{DDA} + 0.5)}{I_{INJmax}}$$

#### Equation 2

$$R_s + R_f \geq \frac{V_{amin} - 0.3}{I_{INJmin}}$$

Being  $V_{DDA} + 0.5$  the positive clamping voltage and  $-0.3$  the negative clamping voltage.

The next condition comes from the analogue source bandwidth  $f_0$ . The filter are designed to cut the noise. Being  $f_f$  the cut-off frequency of the filter, we have:

#### Equation 3

$$f_f = \frac{1}{2\pi R_f (C_f + C_p)} = f_0$$

On the other hand, to prevent aliasing, according to the Nyquist theorem, the frequency  $f_N$  be at least  $2f_0$ :

#### Equation 4

$$f_N = \frac{1}{T_N} = \frac{1}{(T_s + T_c)} \geq 2f_0 = \frac{1}{\pi R_f (C_f + C_p)}$$

Where  $T_s$  is the sampling time and  $T_c$  is the conversion time.  $T_s$  is configurable (2, 8, 64, 128 ADC clock cycles), while  $T_c$  is 13 ADC clock cycles for a differential conversion and 14 for a single ended conversion.

Finally  $T_s$  is chosen to allow the charge sharing to be complete.

When the conversion switch closes, the charges between the capacitors are shared, producing a new voltage that depends upon the initial voltages and the size of the capacitors. This process takes place at the rate of the internal ADC time constant ( $R_{sw}C_s$ ). At the same time the charge share voltage starts to recover towards the actual sample voltage at the rate of the external RC time constant  $R_f(C_f+C_p)$ . Even if the two processes are interdependent, they can be treated as separated, as long as the internal time constant is much smaller than the external one.

Being  $V_s$  the sample voltage and  $V_1$  the voltage after the charge sharing:

#### Equation 5

$$(C_f + C_p)V_s = (C_f + C_p + C_s)V_1$$

Therefore:

#### Equation 6

$$V_1 = \frac{(C_f + C_p)}{C_f + C_p + C_s} V_s$$

happening with an exponential law which time constant is:

#### Equation 7

$$\tau_1 = R_{sw}C_s$$

Then the voltage  $V_1$  recovers exponentially towards  $V_s$  with the time constant:

#### Equation 8

$$\tau_2 = R_f(C_f + C_p)$$

Normally the latter is much larger than the first. This gives us the final constraint:

**Equation 9**

$$\tau_1 \ll \tau_2 \ll T_s$$

However the last constraint can't be always fulfilled. For example when the time constant  $R_f(C_f+C_p)$  has to be big in order to filter out very low frequencies. In this case it is preferable to reduce the resistor  $R_f$  (as long as the current limitation constraint is kept) and increase  $C_f$ : it results in a very small drop due to the charge sharing and eventually a small or negligible error.

**EXAMPLE 1**

Let's assume that:

- $V_{amax} = 12V$
- $R_s = 100\Omega$
- $f_0 = 100KHz$

Using the [Equation 1](#):

$$R_f \geq \frac{12 - 5.5}{3 \cdot 10^{-3}} - 100 \cong 2K\Omega$$

Let's choose  $R_f = 2.2K\Omega$ .

Then, from the [Equation 3](#):

$$C_f = \frac{1}{2\pi \cdot 100 \cdot 10^3 \cdot (2.2 \cdot 10^3)} = 723pF$$

Let's choose  $C_f = 680pF$ .

Then, from the [Equation 4](#):

$$T_s + T_c = \frac{1}{(200 \cdot 10^3)} = 5\mu s$$

Clocking the ADC at its maximum frequency (16MHz):

$$T_s = 80 - 14 = 66 \text{ ADC clock cycles}$$

Let's choose  $T_s = 64$  and continuous conversion.

The external RC time constant  $R_f(C_f + C_p)$  is  $1.496 \mu\text{s}$ , therefore  $T_s$  is about 3 times that constant, meaning that the second exponential transient is not really over. However, the voltage drop due to the charge share is only ([Equation 6:](#))  $4.41 \text{ mV}$  (worst case<sup>(n)</sup>), leading to a negligible error (being  $T_s = 3 \times$  time constant).

### EXAMPLE 2

Let's assume that:

- $V_{\text{amax}} = 24 \text{ V}$
- $R_s = 100 \Omega$
- $f_0 = 50 \text{ Hz}$

Using the [Equation 1:](#)

$$R_f \geq \frac{24 - 5.5}{3 \cdot 10^{-3}} - 100 \cong 6 \text{ k}\Omega$$

Let's choose  $R_f = 6.2 \text{ k}\Omega$ .

Then, from the [Equation 3:](#)

$$C_f = \frac{1}{2\pi \cdot 50 \cdot (6.2 \cdot 10^3)} = 513 \text{ nF}$$

Let's choose  $C_f = 470 \text{ nF}$ .

In this case, being the signal slow, we can simply choose the maximum sampling time:  $T_s = 128$ . Then the ADC can be triggered by an internal timer to meet the Nyquist requirement  $f_N = 2f_0$ .

The capacitance  $C_f$  is much bigger than the internal one, leading to a negligible voltage drop and hence basically no conversion errors due to the charge sharing, hence allowing potentially even smaller sampling times, reducing the overall conversion time.

---

n. The worst case is  $3.75 \text{ V}$ , difference between the sample voltage and the residual voltage on the sample capacitance.

## 4.1 Alternative approach

In some cases the filtering using the RC might not be effective. Instead of using costly active external analogue filters, an internal digital filtering can be implemented using the decimation filter. The approach is the following:

1. Choose a simple RC outside filter which cut-off frequency is much higher than the interested bandwidth of the signal, including the noise.
2. Oversample the signal, potentially sampling at the maximum frequency allowed by the ADC
3. Filter the noise out using the IIR / FIR feature
4. Decimate

For example this approach can be very effective to threat knock sensors outputs, in which the big noise cannot be easily filtered out using a simple RC.

## 5 Reset

In the SPC564Axx / SPC563Mxx devices two reset related pins are implemented:

- /RESET
- /RSTOUT

being respectively the reset input and the reset output.

### 5.1 /RESET

The /RESET pin is an active low input. The RESET pin is asserted by an external device during a power-on or external reset. The internal reset signal asserts only if the RESET pin asserts for 10 clock cycles.

Assertion of the /RESET pin while the device is in reset causes the reset cycle to start over. The /RESET pin has a glitch detector which detects spikes greater than two clocks in duration that fall below the switch point of the input buffer logic of the VDDEH input pins. The switch point lies between the maximum VIL and minimum VIH specifications for the VDDEH input pins.

### 5.2 /RSTOUT

The /RSTOUT pin is an active low output that uses a push/pull configuration. The /RSTOUT pin is driven to the low state by the MCU for all internal and external reset sources.

Depending on the PLL configuration, External Reference or Crystal Mode, the /RSTOUT pin is asserted after a different delay depending on the reset source<sup>(o)</sup>, plus four cycles for sampling of the configuration pins.

The /RSTOUT pin can also be asserted by a write to the SER bit of the System Reset Control Register (SIU\_SRCR).

### 5.3 Reset source description

The table below summarizes the reset sources and their effect on the system.

---

o. Refer to the device reference manual.

Table 7. Reset source description

Reset source <sup>(1)</sup>	SRAM	JTAG <sup>(2)</sup>	Registers (including PMC <sup>(3)</sup> , PLL, etc.)	OSC <sup>(4)</sup>	PORT PIN	BA M	WKPCFG, PLLREF, BOOTCFG	Factory trimming	Shadow information (NVUSR0, Lock Registers, etc.)
POR/LVI	Random content / Retention not reliable	X	X	Not affected	Reset state as per signal properties table (5)	Executed	Sampled	Trimming reloaded from Flash	Reloaded from Flash
ER / LLR / LCR / WTDR / JTAG Reset / SSR	Content unaffected	Not affected	X <sup>(6)</sup>	Not affected	Reset state as per signal properties table (7)	Executed	Sampled	Trimming kept	Reloaded from Flash
SER	Content unaffected	Not affected	Not affected	Not affected	Not affected	Not executed	Not Sampled	Trimming kept	Not reloaded from Flash

1. POR: Power-on Reset / LVI: Low Voltage Inhibit / ER: External Reset / LLR: Loss of Lock Reset / LCR: Loss of Clock Reset / WTDR: Watchdog Timer/Debug Reset / SSR: Software System Reset / SER: Software External Reset

2. JCOMP is used to reset JTAG Controller

3. Including MCR register

4. Provided that the supply voltages are within the limits

5. Refer to RM / DS

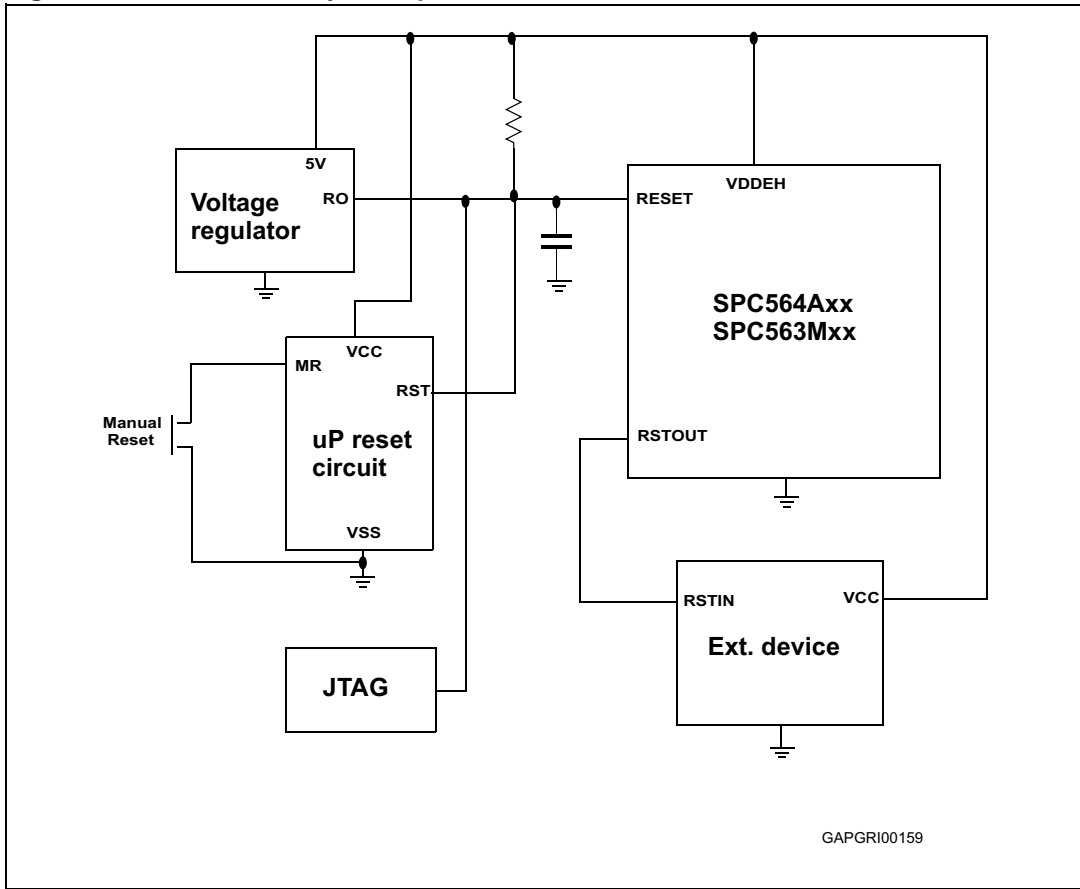
6. RAM content unaffected (CAN message buffer, ETPU memories, etc.)

7. Refer to RM / DS



### 5.4 Reset circuitry example

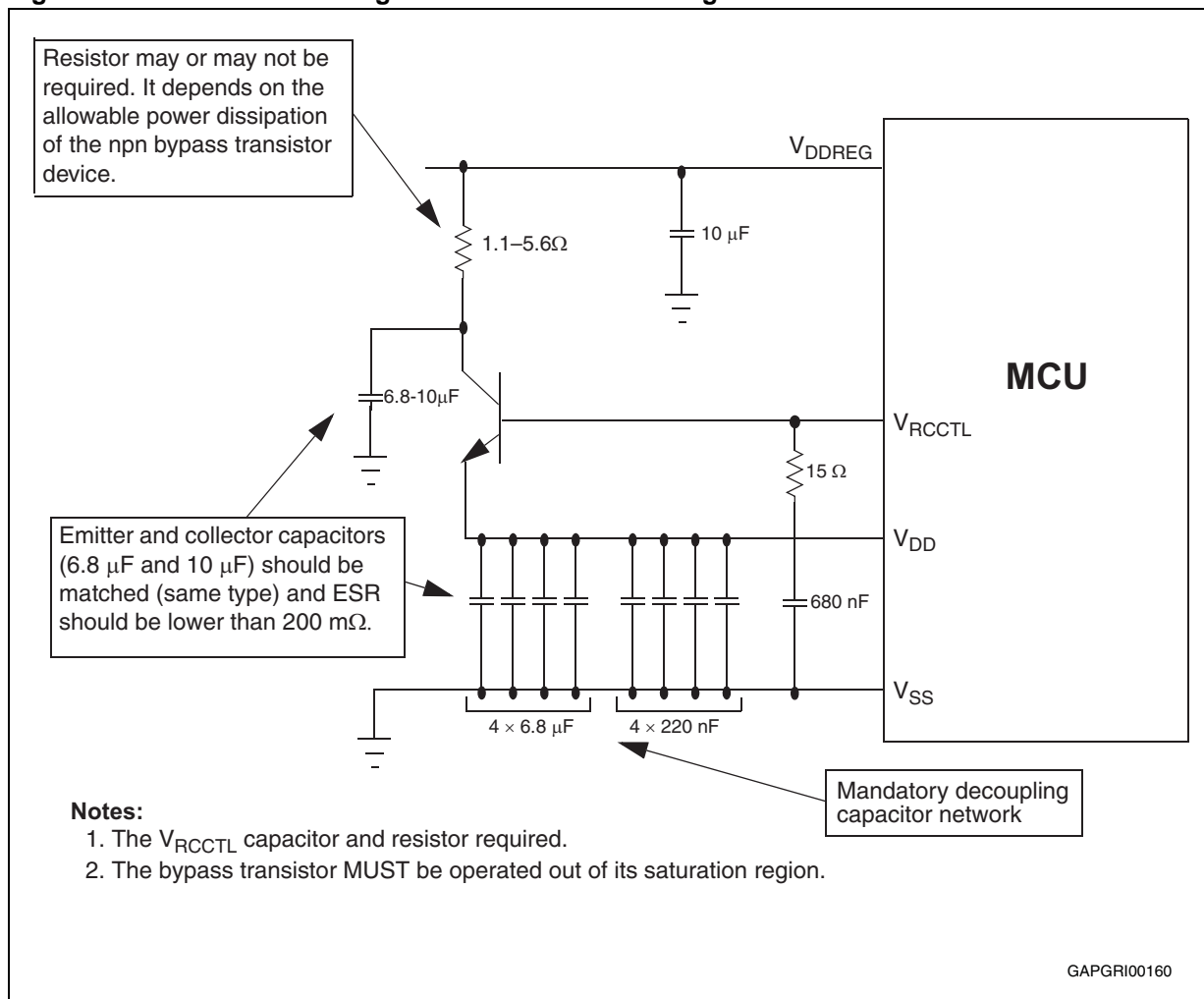
Figure 11. Reset circuitry example



## Appendix A Previous recommended PMC network configurations

Figure 12 shows an old recommended configuration that was proven to be unstable in some corner cases, especially with NJD2873.

Figure 12. SPC563Mxx configuration/SPC564Axx configuration

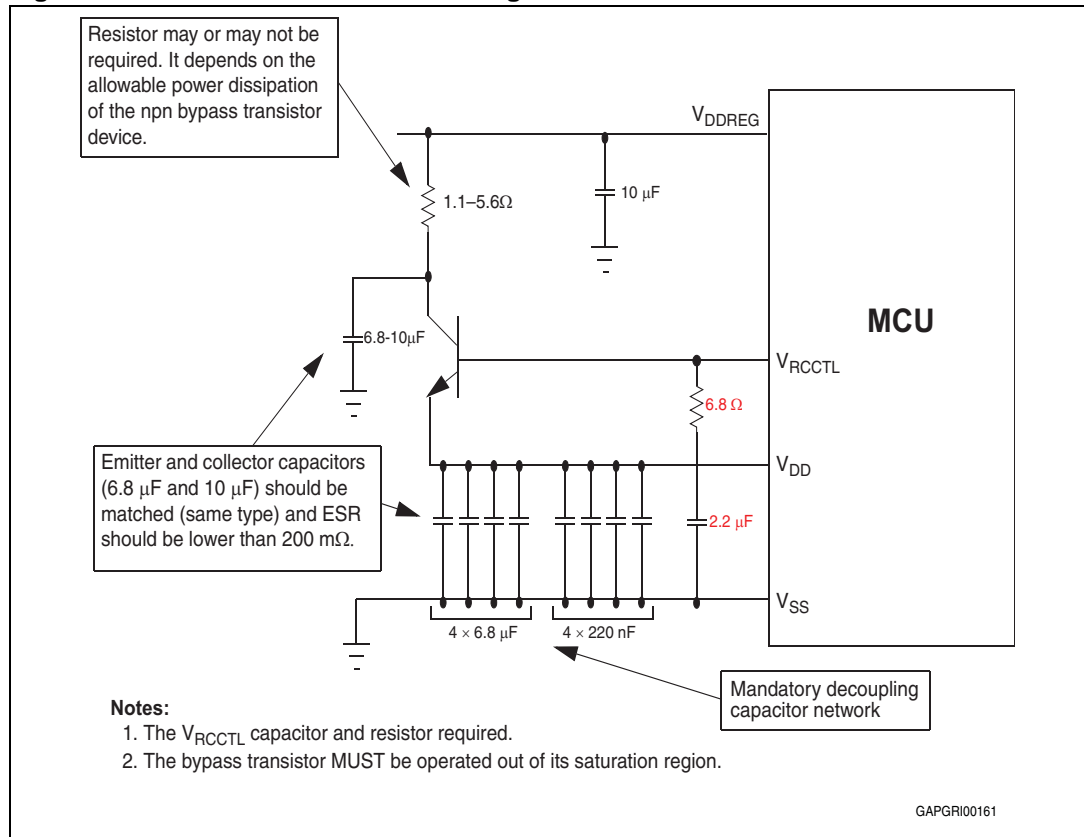


However, when the ballast transistor in use is BCP68, this configuration is still safe to use with SPC563Mxx. With a small modification to the snubber network on the base (see Figure 13), it is safe with NJD2873 too.

The configuration shown in Figure 12 must never be used in any SPC564Axx design.

Note: Figure 12 is not present in last versions of Datasheet and Reference manual as it is outdated (for further information see Section Appendix B: Further information).

Figure 13. Alternate SPC563Mxx configuration



## Appendix B Further information

### B.1 Reference documents

- *32-bit MCU family built on the embedded Power Architecture®* (SPC564A74B4, SPC564A74L, SPC564A80B4, SPC564A80L7, Doc ID 15399)
- *32-bit MCU family built on the embedded Power Architecture®* (RM0029, Doc ID 15117)
- *32-bit Power Architecture® based MCU for automotive powertrain applications* (SPC563M64, Doc ID 14642)
- *SPC563M64xx - 32-bit Power Architecture® based MCU with up to 1.5 Mbyte Flash and 111 Kbyte RAM memories* (RM0015, Doc ID 14499)

## Revision history

**Table 8. Document revision history**

Date	Revision	Changes
02-May-2012	1	Initial release.
17-Sep-2013	2	Updated disclaimer.

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